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STANDARDIZED CHE MILITARY DRAWING APP				Marcia B Kelleher CHECKED BY ONN APPBROXED BY APPBROXE					MICROCIRCUITS, DIGITAL, DUAL-J-K FLIP-FLOP, MON				O 454	HIGH-SPEED CMOS												
FOR USE BY AND AC DEPARTA	THIS DRAWING IS AVAILABLE OR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE DRAWING APPROVAL LATE 2 JULY 1986 REVISION LEVEL					SIZE A				33		5	96	32-	85	15	3									
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DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

1. SCOPE				···	in the second second		
1.1 Scope. This drawing describes dev with 1.2.1 of MIL-STD-883, "Provisions fo non-JAN devices".	vice requi or the use	rement of MI	s for class B L-STD-883 in (microcircu conjunction	ifts in accordance with compliant		
1.2 Part number. The complete part no	umber shal	1 be a	s shown in the	e following	g example:		
5962-85153 <u>01</u>		C T		X T			
l j Drawing number Device type (1.2.1)	_	outl1 .2.2)		 ad finish p L-M-38510	er		
1.2.1 Device type. The device type sh	nall ident	ify th	e circuit fund	tion as fo	llows:		
Device type Generic number			Circuit				
01 54HC73	D	ual J-	K flip-flop wi	ith reset			
1.2.2 <u>Case outlines</u> . The case outline as follows:	es shall b	e as d	esignated in a	appendix C	of MIL-M-38510, an	ıd	
Outline letter		Case	outline				
C D-1 (14-1 2 C-2 (20 t	ead, .785	" x .3	10" x .200"),	dual-in-li	ne package		
- 100 terminary, 1000 X 1000 Y, Square Chip Carrier package							
Supply voltage range							
STANDARDIZED	SIZE A			Enc	2 05152		
MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER		L	REVISION LEVEL	-	2-85153 SHEET	ᅦ	
DAYTON, OHIO 45444				Α	2		

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Minimum setup time, J or K to clock (t_s):

T_C = +25°C, V_{CC} = 2.0 \text{ V} - - -
                                                                   100 ns
                                                                                                                                                                          20 ns
          T_{C} = -55^{\circ}C/+125^{\circ}C
                                                                   30 ns
   Minimum recovery time, reset inactive to clock (trec):
                                                                  T_C = +25^{\circ}C
                                                                                                                                                                       100 ns
                                                                                                                                                                         20 ns
        T_{C} = -55^{\circ}C/+125^{\circ}C,
                                                                  Minimum clock pulse width (t_W): V_{CC} = 2.0 \ V_{CC} = 2.5 \ V_{CC} = 4.5 \ V_{CC} = -1.5 \ V_{CC} = -1.
                                                                  VCC = 4.5 V - - - - - - VCC = 6.0 V - - - - - -
                                                                                                                                                                         15 ns
                                                                 T_{C} = -55^{\circ}C/+125^{\circ}C
                                                                                                                                                                        27 ns
  Minimum reset pulse width (t_w):
                                                                 T_C = +25^{\circ}C
                                                                                                                                                                     100 ns
       T_{C} = -55^{\circ}C/+125^{\circ}C
                                                                 150 ns
                                                                                                                                                                       30 ns
 5 ns
                                                                                                                                                                          5 ns
                                                                T_{C} = -55^{\circ}C/+125^{\circ}C,
                                                                                                                                                                       40 ns
                                                                                                                                                                         8 ns
5.4 MHz
                                                                                                                                                                      32 MHz
     T_{C} = -55^{\circ}C/+125^{\circ}C
                                                                V<sub>CC</sub> = 2.0 V - - - - - - - - -
                                                                                                                                                                         3.6 MHz
                                                               18 MHz
                                                                                                                                                                      21 MHz
                     STANDARDIZED
                                                                                                                  SIZE
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           MILITARY DRAWING
                                                                                                                                                                                                     5962-85153
       DEFENSE ELECTRONICS SUPPLY CENTER
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                            DAYTON, OHIO 45444
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2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
 - REQUIREMENTS
- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-M-38510, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2.1 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.
 - 3.2.3 Truth table. The truth table shall be as specified on figure 2.
 - 3.2.4 Logic diagram. The logic diagram shall be as specified on figure 2.
 - 3.2.5 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.
- $3.4\,$ Marking. Marking shall be in accordance with MIL-STD-883 (see $3.1\,$ herein). The part shall be marked with the part number listed in $1.2\,$ herein. In addition, the manufacturer's part number may also be marked as listed in $6.4\,$ herein.

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Test	Symbo1	Conditions $1/$ $-55^{\circ}C < T_{C} < +175^{\circ}C$ unless otherwise specified			Group A subgroups	Limits Min Max		Unit
High level output	i v _{OH}	AIN = AIH	or V _{IL}	V _{CC} = 2.0 V	11, 2, 3	1.9	Max	V
voltage		 I ₀ <u><</u> 20 	μA	V _{CC} = 4.5 V		4.4		
	 	1 1 1		V _{CC} = 6.0 V	- 	5.9		
	 	V _{IN} = V _{IH} I _O < 4.0		V _{CC} = 4.5 V	~-i	3.7		
		V _{IN} = V _{IH} I _O < 5.2		V _{CC} = 6.0 V		5.2		
Low level output voltage	v _{OL}	AIN = AIH	or V _{IL}	V _{CC} = 2.0 V	1, 2, 3		0.1	٧
		I ₀ <u><</u> 20	μA	V _{CC} = 4.5 V	i		0.1	
] 		VCC = 6.0 V			0.1	
	- 	V _{IN} = V _{IH} 		V _{CC} = 4.5 V		1	0.4	
		V _{IN} = V _{IH}		V _{CC} = 6.0 V		 	0.4	
High level input voltage	I V I H	2/		V _{CC} = 2.0 V	1, 2, 3	1.5	i	٧
vortuge	1			V _{CC} = 4.5 V	j ; 	3.15	i 	
				V _{CC} = 6.0 V	_i	4.2	——i	
See footnotes at end	of table.	•	4.4		<u>'</u>			
STANDA		10	SIZE A		5962-8	5152		
MILITARY I			<u> </u>	REVISION LEVEL		SHEET		

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TABLE I. Electrical performance characteristics - Continued. Conditions 1/ -55°C < T_C < +1 $\overline{2}$ 5°C unless otherwise specified Test Symbol Group A Limits Unit subgroups Min | Max Low level input voltage $|V_{IL}|$ 2/ V_{CC} = 2.0 V 11, 2, 3 ٧ 0.3 $V_{CC} = 4.5 \text{ V}$ 0.9 VCC = 6.0 V 1.2 Input capacitance $V_{IN} = 0 V$, $T_{C} = +25^{\circ}C$ | See 4.3.1c CIN 10 pΕ Quiescent current ICC VCC = 6.0 V, VIN = VCC or GND 1, 2, 3 80 μΑ Input leakage current IIN $V_{CC} = 6.0 \text{ V}, V_{IN} = V_{CC} \text{ or GND}$ 1, 2, 3 ±1 μА Functional tests See 4.3.1d 7 Propagation delay time; clock to Q or Q TC = +25°C |C_L = 50 pF | ±10% V_{CC} = 2.0 V tPHL1, 9 170 ns tPLH1 V_{CC} = 4.5 V 34 3/ See figure 3 $V_{CC} = 6.0 \text{ V}$ 29 $T_C = -55^{\circ}C$ and $+125^{\circ}C$ $V_{CC} = 2.0 \text{ V}$ 10, 11 255 ns C_L = 50 pF + 10% $V_{CC} = 4.5 \text{ V}$ 51 See figure 3 V_{CC} = 6.0 V 43

See footnotes at end of table.

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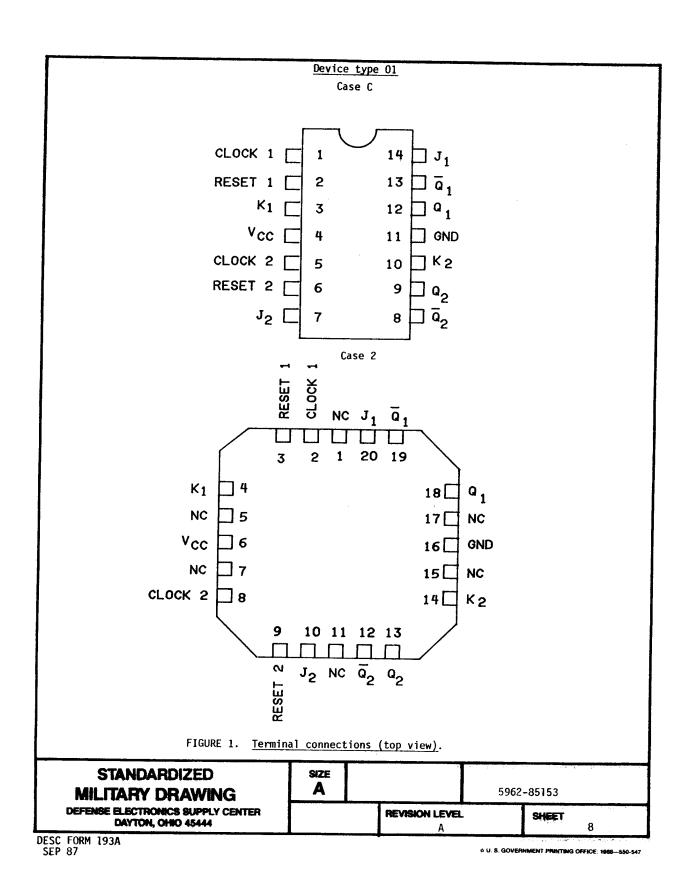
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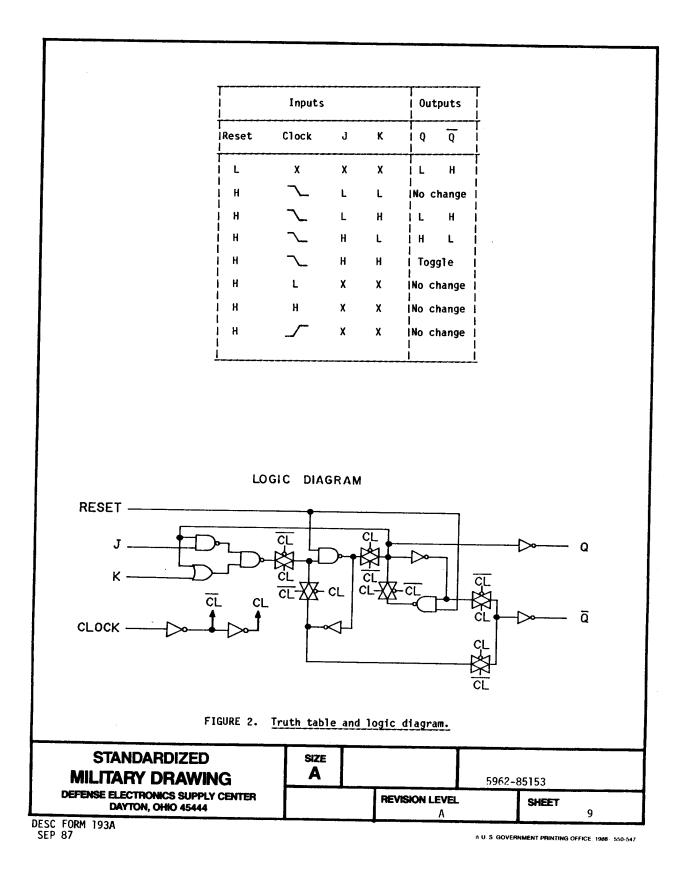
Test	Symbol	Conditions -55°C < T _C <	Conditions 1/ -55°C < T _C < +125°C				l Unit T
		unless otherwise		Min	Max		
Propagation delay time; reset to Q or Q	tpHL2.	T _C = +25°C C _L = 50 pF ±10%	V _{CC} = 2.0 V	9 9 1		155	ns
<u>3</u> /	i 	See figure 3	V _{CC} = 4.5 V		1	31	
			V _{CC} = 6.0 V			26	
	; 	T _C = -55°C and +125°C	V _{CC} = 2.0 V	10, 11		235	ns
	[C _L = 50 pF ±10%	V _{CC} = 4.5 V		 	47	
		 See figure 3	V _{CC} = 6.0 V			40	
ransition time, any output 4/	t _{THL} , t _{TLH}	 T _C = +25°C C _L = 50 pF ±10%	V _{CC} = 2.0 V	9		75	ns
		See figure 3	V _{CC} = 4.5 V			15 	
	<u> </u>		V _{CC} = 6.0 V			13	
ļ		$T_C = -55^{\circ}C$ and $+125^{\circ}C$	V _{CC} = 2.0 V	10, 11		110	ns
		C _L = 50 pF ±10%	V _{CC} = 4.5 V			22	
 	!	See figure 3	V _{CC} = 6.0 V	! 		19	

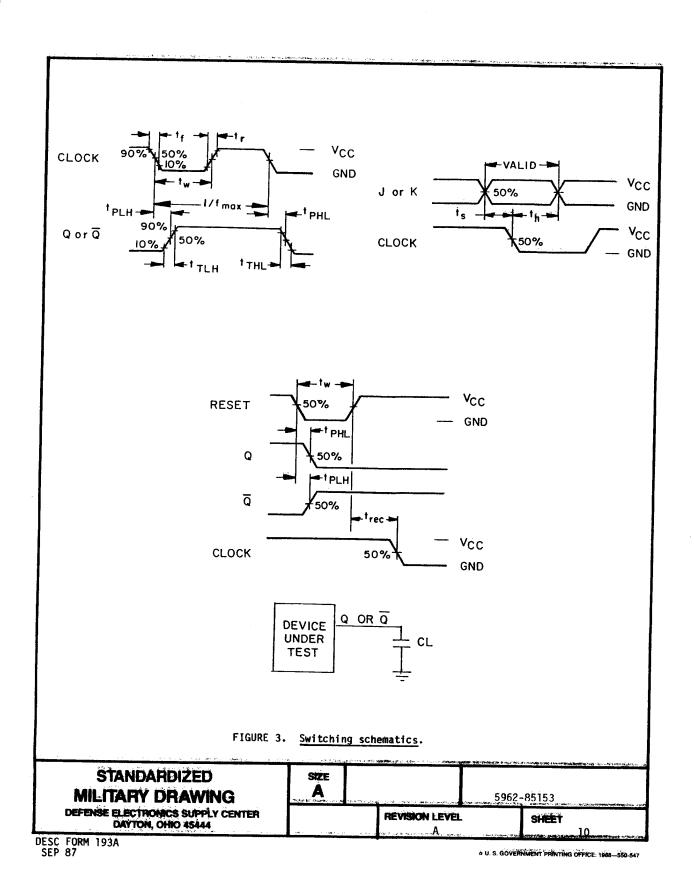
- For a power supply of 5 V $\pm 10\%$, the worse case output voltages (V_{OH} and V_{OL}) occur for HC at 4.5 V. Thus, the 4.5 V values should be used when designing with this supply. Worst case VIH and VIL occur at VCC = 5.5 V and 4.5 V respectively. (The VIH value at 5.5 V is 3.85 V.) The worst case leakage current (I_{IN} , I_{CC} , and I_{OZ}) occur for CMOS at the higher voltage and so the 6.0 V values should be used. Power dissipation capacitance (C_{PD}), typically 40 pF, determines the no load dynamic power consumption, $P_{D} = C_{PD}$ VCC²⁺¹CCV, and the no load dynamic current consumption, $I_{S} = C_{PD}$ VCC²⁺¹CCC.
- $\underline{2}/$ Test not required if applied as a forcing function for v_{OH} or v_{OL} .
- $\frac{3}{}$ AC testing at V_{CC} = 2.0 V and V_{CC} = 6.0 V shall be guaranteed, if not tested, to the specified limits.
- $\underline{4}$ / Transition time (t_{TLH}, t_{THL}), if not tested, shall be guaranteed to the specified limits.

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- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-SID-883 (see 3.1 herein).
- 3.8 <u>Verification and review.</u> DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section $\overline{4}$ of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening.</u> Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method $\overline{5005}$ of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - c. Subgroup 4 ($C_{\rm IN}$ measurement) shall be measured only for the initial test and after process or design changes which may affect capacitance. Test all applicable pins on 5 devices with zero failures.
 - d. Subgroup 7 tests sufficient to verify the truth table.

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4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements 	Subgroups Subgroups (per method 5005, table I)
 Interim electrical parameters (method 5004)	I
 Final electrical test parameters (method 5004)	1*, 2, 9
 Group A test requirements (method 5005)	 1, 2, 3, 4, 7, 9, 10**, 11**
 Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

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PDA applies to subgroup 1. Subgroups 10 and 11, if not tested, shall be guaranteed to the specified limits in table I.

- 6.2 Replaceability. Replaceability is determined as follows:
 - a. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
 - b. When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as part number M38510/65301B--.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.
- 6.4 Approved sources of supply. Approved sources of supply are listed herein. Additional sources will be added as they become available. The vendors listed herein have agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1</u> /	Replacement military specification part number
5962-8515301CX	04713 18714 27014	54HC73/BCAJC CD54HC73F/3A MM54HC73J/883	M38510/65301BCX
5962-85153012X	04713	54HC73M/B2AJC MM54HC73E/883	M38510/65301B2X

 $\frac{1}{}$ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number	Vendor name and address
04713	Motorola, Incorporated 7402 S. Price Road Tempe, AZ 85283
18714	GE/RCA Corporation Solid State Division Route 202 Somerville, NJ 08876
27014	National Semiconductor 333 Western Avenue South Portland, ME 04106

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